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Application/Control No.	Applicant(s)/Patent under Reexamination					
10/821,500	SHEN ET AL.					
Examiner	Art Unit					
Jezia Riley	1637	•				

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Class	Subclass	Date	Examiner
544	232,277		
546	23,24,113		
536	26.6		
435	6,91.1	12/15/2006	JR

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
STN search enclosed	12/15/2006	JR			
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